

**Search Notes**

Application/Control No.

10/774,883

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

FUNG ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	6,9,10,16, 18	2/3/2006	PK
716	16,18	2/7/2006	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Class/sub searched: 716/1-18 (see attached)	2/3/2006	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	2/3/2006	PK
IEE/IEEE XPlore (see attached)	2/3/2006	PK
BRS (EAST) --USPAT, USPGPUB Class/Sub searched: 16,18	2/7/2006	PK